

Search Notes

Application/Control No.

10/692,269

Examiner

HABTE MERED

Applicant(s)/Patent under
Reexamination

LIAO ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	230	4/25/2008	HM
370	230.1	4/25/2008	HM
370	231	4/25/2008	HM
370	232	4/25/2008	HM
370	233	4/25/2008	HM
370	234	4/25/2008	HM
370	449	4/25/2008	HM
709	225-229	4/25/2008	HM
455	450	4/25/2008	HM
455	452.1	4/25/2008	HM
455	452.2	4/25/2008	HM
455	453	4/25/2008	HM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched East DB:USPAT, USPG-PUB, EPO and JPO	4/25/2008	HM
Searched IEEE	4/25/2008	HM
Searched Palm Inventor's DB	4/25/2008	HM